

**Search Notes**

Application/Control No.

10/528,608

Examiner

John D. Lee

Applicant(s)/Patent under  
Reexamination

NEVO ET AL.

Art Unit

2874

**SEARCHED**

Class	Subclass	Date	Examiner
385	27-32, 140,147	11/15/2006	JDL
359	227-236	11/15/2006	JDL
250	229	11/15/2006	JDL
356	437	11/15/2006	JDL
(To	Date)		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO "WEST" Database searched; search strategy on separate sheet.	11/15/2006	JDL